



2877

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Atty. Docket

MARTIN FUCHS ET AL

PHA 23,578

Serial No. 09/087,141

Group Art Unit 3642

Filed: MAY 28, 1998

Examiner:

METHOD AND DEVICE FOR MEASURING THIN FILMS AND SEMICONDUCTOR SUBSTRATES

Honorable Commissioner of Patents and Trademarks  
Washington, D.C. 20231

LETTER TO OFFICIAL DRAFTSMAN

Sir:

Enclosed are 7 sheets of formal drawings  
for filing in the above-identified application.

Respectfully submitted,

By *A. E. Barschall*  
Anne E. Barschall, Reg. 31,089  
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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being  
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first-class mail in an envelope addressed to:

COMMISSIONER OF PATENTS AND TRADEMARKS  
Washington, D.C. 20231

On 5/16/99  
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By *A. E. Barschall*  
(Signature)

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